2014 International Symposium on Dependable Integrated Systems

March 10, 2014
Graduate Seminar Room 7F, General Research Building, Iizuka Campus, Kyutech
Dependable Integrated Systems Research Center
Kyushu Institute of Technology

■ 09:30~09:40: Opening & Introduction to DISC
Xiaoqing Wen, DISC, Kyutech, Japan

■ 09:40~10:30: Invited Talk 1
- Using FPGAs in Automotive & Industrial Applications
  Brad Kadet, Altera, USA

■ 10:30~11:20: Invited Talk 2
- Implementation of ATE Timing Circuits on FPGA
  Jiun-Lang Huang, National Taiwan University, Taiwan

■ 11:20~12:10: Invited Talk 3
- Why I Started My Own Company at the Age of 29?
  - My perspective on future work shift through my career of 6 years and in 3 countries -
  Shusei Hanibuchi, Capsule Inc., Japan

■ 12:10~13:20: Lunch

■ 13:20~15:00: DISC-Presentation-I
  Chair: Stefan Holst, DISC, Kyutech, Japan
  - Algorithm and Hardware Design of a Quasi MLD Decoder for MIMO Systems
    Hong Trang Thi, Yuhei Nagao, Hiroshi Ochi
  - Hardware Implementation of a MIMO Channel Emulator
    Tran Thi Thao Nguyen, Leonardo Lanante, Yuhei Nagao, Hiroshi Ochi
  - High Definition Video Transmission System using Channel Characteristics
    Masafumi Ito, Koji Tashiro, Daiki Sakata, Masayuki Kuroasaki, Hiroshi Ochi
  - Mosaic SRAM Cell TEGs with Intentionally-Added Device Variability for Confirming the Ratio-less SRAM Operation
    Hitoshi Okamura, Takahiko Suzuki, Hiroaki Goto, Masahiro Yamamoto, Kazuyuki Nakamura

■ 15:00~15:20: Break

■ 15:20~17:00: DISC-Presentation-II
  Chair: Kohei Miyase, DISC, Kyutech, Japan
  - A Stabilization Technique for Intermediate Power Level in Stacked-Vdd ICs using Parallel I/O Signal Coding
    Naoya Kabo, Tomofumi Nishiyama, Taiki Koizuka, Hitoshi Okamura, Tomoyuki Yamanokuchi, Kazuyuki Nakamura
  - Test Power Reduction for Logic-BIST
    Senling Wang, Yasuo Sato, Seiji Kajihara, Kohei Miyase
  - A Temperature and Voltage Monitor for Field Test
    Yousuke Miyake, Yasuo Sato, Seiji Kajihara, Yukiya Miura
  - Study on X-Filling of Test Pattern for Low-Power Test
    Fuqiang Li, Kohei Miyase, Stefan Holst, Xiaoqing Wen

■ 17:00~17:05: Closing
Seiji Kajihara, DISC, Kyutech, Japan